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PERFORMANCE CHECKSHEET

Model: AVR-EB4-B  
Type: Semiconductor Device Tester  
S.N.: 12349  
Date: December 3, 2009

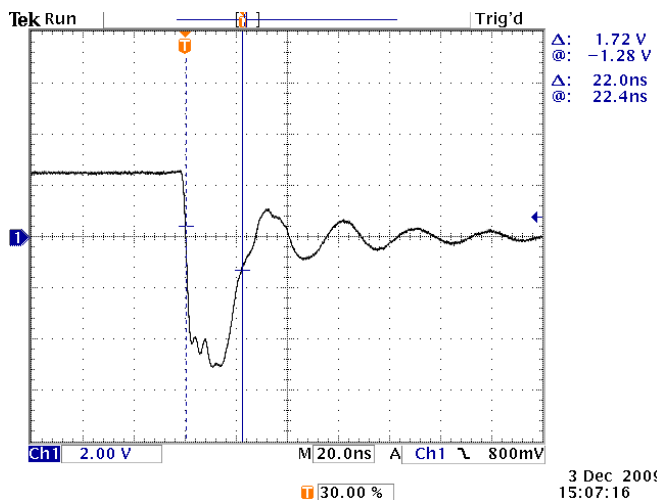
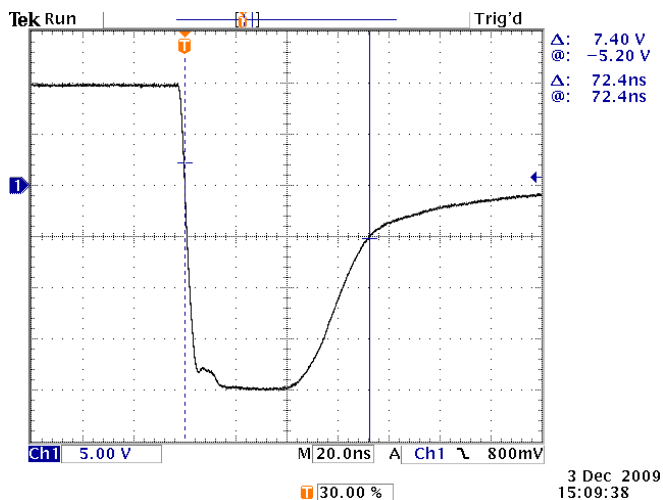
Output Amplitude: to +2A, -4A  
Pulse Width (FWHM): 2 – 20 us  
Switching Time,  
+ to -, 10%-90%: ≤ 4.5 ns  
PRF: 1 - 100 Hz  
Jitter, Stability: OK  
Prime Power: 100-240V AC, 50-60 Hz.

Basic specifications: →

Test Waveforms

With an On Semi 1N4937 installed in the AVX-TRR-MIX test jig, connected using the 60 cm / 24" coaxial cable:

With a Microsemi MQ1N5811US installed in the AVX-TRR-SQMELF test jig (S/N 12351), connected using the 60 cm / 24" coaxial cable:



$I_F = +2A, I_R = -4A, I_{RR} = -1A.$

$I_F = +0.5A, I_R = -1A, I_{RR} = -0.25A.$

100 Hz, 20 us PW.

100 Hz, 20 us PW.

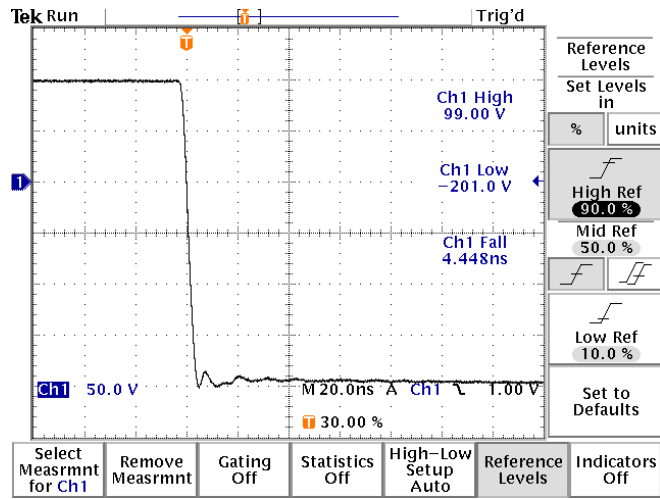
5V (1A) / div, 20 ns/div.

2V (0.4A) / div, 20 ns/div.

Measured  $t_{RR} = 72.4$  ns.

Measured  $t_{RR} = 22.0$  ns.

Mainframe output, into 50 Ohms:



50 V / div, 20 ns/div. +100V, -200V.

10% - 90% fall time shown.